

Notice of References Cited		Application/Control No. 10/558,514	Applicant(s)/Patent Under Reexamination KSHIRSAGAR ET AL.	
		Examiner Nikki H. Dees	Art Unit 1794	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,423,358 B1	07-2002	Barndt et al.	426/548
*	B	US-2004/0258822 A1	12-2004	Liao et al.	426/548
*	C	US-5,227,182 A1	07-1993	Song et al.	426/5
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 545890 A2	06-1993	European Patent	DAENKINDT et al.	A23L 01/236
	O	JP 2000037169 A	02-2000	Japan	OKUMA et al.	A23L 01/22
	P	JP 2002136270 A	05-2002	Japan	FUJITA et al.	A23L 01/236
	Q	CA 1076110 A1	04-1980	Canada	HOUGH et al.	A23L 01/226
	R	WO 99/30577	06-1999	WIPO	PONKALA et al.	A23L 01/236
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

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